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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	I ² C, SPI, UART/USART
Peripherals	DMA, PWM, WDT
Number of I/O	46
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	24K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 2x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkv31f128vlh10p

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1 Ratings

1.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T _{STG}	Storage temperature	−55	150	°C	1
T _{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model	−2000	+2000	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model	−500	+500	V	2
I _{LAT}	Latch-up current at ambient temperature of 105°C	−100	+100	mA	3

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.
3. Determined according to JEDEC Standard JESD78, *IC Latch-Up Test*.

1.4 Voltage and current operating ratings

Table 1. Voltage and current operating requirements (continued)

Symbol	Description	Min.	Max.	Unit	Notes
V_{DDA}	Analog supply voltage	1.71	3.6	V	
$V_{DD} - V_{DDA}$	V_{DD} -to- V_{DDA} differential voltage	-0.1	0.1	V	
$V_{SS} - V_{SSA}$	V_{SS} -to- V_{SSA} differential voltage	-0.1	0.1	V	
V_{IH}	Input high voltage $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ $1.7\text{ V} \leq V_{DD} \leq 2.7\text{ V}$	$0.7 \times V_{DD}$	—	V	
		$0.75 \times V_{DD}$	—	V	
V_{IL}	Input low voltage $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ $1.7\text{ V} \leq V_{DD} \leq 2.7\text{ V}$	—	$0.35 \times V_{DD}$	V	
		—	$0.3 \times V_{DD}$	V	
V_{HYS}	Input hysteresis	$0.06 \times V_{DD}$	—	V	
I_{ICIO}	Analog and I/O pin DC injection current — single pin $V_{IN} < V_{SS}-0.3\text{V}$ (Negative current injection)	-3	—	mA	1
I_{ICcont}	Contiguous pin DC injection current — regional limit, includes sum of negative injection currents or sum of positive injection currents of 16 contiguous pins Negative current injection	-25	—	mA	
V_{ODPU}	Open drain pullup voltage level	V_{DD}	V_{DD}	V	2
V_{RAM}	V_{DD} voltage required to retain RAM	1.2	—	V	

1. All analog and I/O pins are internally clamped to V_{SS} through ESD protection diodes. If V_{IN} is less than V_{IO_MIN} or greater than V_{IO_MAX} , a current limiting resistor is required. The negative DC injection current limiting resistor is calculated as $R=(V_{IO_MIN}-V_{IN})/|I_{ICIO}|$.
2. Open drain outputs must be pulled to V_{DD} .

2.2.2 LVD and POR operating requirements

Table 2. V_{DD} supply LVD and POR operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR}	Falling VDD POR detect voltage	0.8	1.1	1.5	V	
V_{LVDH}	Falling low-voltage detect threshold — high range (LVDV=01)	2.48	2.56	2.64	V	
V_{LVW1H} V_{LVW2H} V_{LVW3H} V_{LVW4H}	Low-voltage warning thresholds — high range					1
	• Level 1 falling (LVWV=00)	2.62	2.70	2.78	V	
	• Level 2 falling (LVWV=01)	2.72	2.80	2.88	V	
	• Level 3 falling (LVWV=10)	2.82	2.90	2.98	V	
	• Level 4 falling (LVWV=11)	2.92	3.00	3.08	V	

Table continues on the next page...

Table 2. V_{DD} supply LVD and POR operating requirements (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{HYSH}	Low-voltage inhibit reset/recover hysteresis — high range	—	80	—	mV	
V_{LVDL}	Falling low-voltage detect threshold — low range (LVDV=00)	1.54	1.60	1.66	V	
V_{LVW1L}	Low-voltage warning thresholds — low range					1
	• Level 1 falling (LVWV=00)	1.74	1.80	1.86	V	
V_{LVW2L}	• Level 2 falling (LVWV=01)	1.84	1.90	1.96	V	
V_{LVW3L}	• Level 3 falling (LVWV=10)	1.94	2.00	2.06	V	
V_{LVW4L}	• Level 4 falling (LVWV=11)	2.04	2.10	2.16	V	
V_{HYSL}	Low-voltage inhibit reset/recover hysteresis — low range	—	60	—	mV	
V_{BG}	Bandgap voltage reference	0.97	1.00	1.03	V	
t_{LPO}	Internal low power oscillator period — factory trimmed	900	1000	1100	μ s	

1. Rising threshold is the sum of falling threshold and hysteresis voltage

2.2.3 Voltage and current operating behaviors

Table 3. Voltage and current operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{OH}	Output high voltage — Normal drive pad except RESET_B					
	$2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OH} = -5\text{ mA}$	$V_{DD} - 0.5$	—	—	V	1
	$1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OH} = -2.5\text{ mA}$	$V_{DD} - 0.5$	—	—	V	
V_{OH}	Output high voltage — High drive pad except RESET_B					
	$2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OH} = -20\text{ mA}$	$V_{DD} - 0.5$	—	—	V	1
	$1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OH} = -10\text{ mA}$	$V_{DD} - 0.5$	—	—	V	
I_{OHT}	Output high current total for all ports	—	—	100	mA	
V_{OL}	Output low voltage — Normal drive pad except RESET_B					
	$2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OL} = 5\text{ mA}$	—	—	0.5	V	1
	$1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OL} = 2.5\text{ mA}$	—	—	0.5	V	
V_{OL}	Output low voltage — High drive pad except RESET_B					
	$2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OL} = 20\text{ mA}$	—	—	0.5	V	1
	$1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OL} = 10\text{ mA}$	—	—	0.5	V	
V_{OL}	Output low voltage — RESET_B					

Table continues on the next page...

Table 5. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	@ 70°C	—	1.78	2.09	μA	
	@ 85°C	—	2.8	3.25	μA	
	@ 105°C	—	4.0	6.15	μA	
I _{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit enabled					
	@ -40°C to 25°C	—	0.40	0.49	μA	
	@ 70°C	—	1.38	1.49	μA	
	@ 85°C	—	2.40	2.70	μA	
	@ 105°C	—	3.6	5.65	μA	
I _{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit disabled					
	@ -40°C to 25°C	—	0.12	0.19	μA	
	@ 70°C	—	1.05	1.13	μA	
	@ 85°C	—	2.1	2.45	μA	
	@ 105°C	—	3.3	5.35	μA	

1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
2. Cache on and prefetch on, low compiler optimization.
3. Coremark benchmark compiled using IAR 7.2 with optimization level low.
4. 100 MHz core and system clock, 50 MHz bus clock, and 25 MHz flash clock. MCG configured for FEE mode. All peripheral clocks disabled.
5. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks disabled.
6. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled.
7. 72 MHz core and system clock, 36 MHz bus clock, and 24 MHz flash clock. MCG configured for FEE mode. All peripheral clocks disabled. Compute operation.
8. 72MHz core and system clock, 36MHz bus clock, and 24MHz flash clock. MCG configured for FEI mode. All peripheral clocks disabled.
9. 72MHz core and system clock, 36MHz bus clock, and 24MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled.
10. 72MHz core and system clock, 36MHz bus clock, and 24MHz flash clock. MCG configured for FEI mode. Compute Operation.
11. 25MHz core and system clock, 25MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode.
12. 4 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. Compute Operation. Code executing from flash.
13. 4 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled. Code executing from flash.
14. 4 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks enabled but peripherals are not in active operation. Code executing from flash.
15. 4 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled.

Table 6. Low power mode peripheral adders—typical value

Symbol	Description	Temperature (°C)						Unit
		-40	25	50	70	85	105	
I _{IREFSTEN4MHz}	4 MHz internal reference clock (IRC) adder. Measured by entering STOP or VLPS mode with 4 MHz IRC enabled.	56	56	56	56	56	56	μA
I _{IREFSTEN32KHz}	32 kHz internal reference clock (IRC) adder. Measured by entering STOP mode with the 32 kHz IRC enabled.	52	52	52	52	52	52	μA
I _{EREFSTEN4MHz}	External 4 MHz crystal clock adder. Measured by entering STOP or VLPS mode with the crystal enabled.	206	228	237	245	251	258	uA
I _{EREFSTEN32KHz}	External 32 kHz crystal clock adder by means of the OSC0_CR[EREFSTEN and EREFSTEN] bits. Measured by entering all modes with the crystal enabled.							
	VLLS1	440	490	540	560	570	580	nA
	VLLS3	440	490	540	560	570	580	
	LLS	490	490	540	560	570	680	
	VLPS	510	560	560	560	610	680	
	STOP	510	560	560	560	610	680	
I _{48MIRC}	48 Mhz internal reference clock	350	350	350	350	350	350	μA
I _{CMP}	CMP peripheral adder measured by placing the device in VLLS1 mode with CMP enabled using the 6-bit DAC and a single external input for compare. Includes 6-bit DAC power consumption.	22	22	22	22	22	22	μA
I _{UART}	UART peripheral adder measured by placing the device in STOP or VLPS mode with selected clock source waiting for RX data at 115200 baud rate. Includes selected clock source power consumption.							
	MCGIRCLK (4 MHz internal reference clock)	66	66	66	66	66	66	μA
	>OSCERCLK (4 MHz external crystal)	214	237	246	254	260	268	
I _{BG}	Bandgap adder when BGEN bit is set and device is placed in VLPx, LLS, or VLLSx mode.	45	45	45	45	45	45	μA
I _{ADC}	ADC peripheral adder combining the measured values at V _{DD} and V _{DDA} by placing the device in STOP or VLPS mode. ADC is configured for low power mode using the internal clock and continuous conversions.	42	42	42	42	42	42	μA

Peripheral operating requirements and behaviors

Board type	Symbol	Description	100 LQFP	64 LQFP	Unit	Notes
		package top outside center (natural convection)				

1. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)* with the single layer board horizontal. Board meets JESD51-9 specification.
2. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)*.
3. Determined according to JEDEC Standard JESD51-6, *Integrated Circuits Thermal Test Method Environmental Conditions—Forced Convection (Moving Air)* with the board horizontal.
4. Determined according to JEDEC Standard JESD51-8, *Integrated Circuit Thermal Test Method Environmental Conditions—Junction-to-Board*.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

3 Peripheral operating requirements and behaviors

3.1 Core modules

3.1.1 SWD electricals

Table 12. SWD full voltage range electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	SWD_CLK frequency of operation • Serial wire debug	0	33	MHz
S2	SWD_CLK cycle period	1/S1	—	ns
S3	SWD_CLK clock pulse width • Serial wire debug	15	—	ns
S4	SWD_CLK rise and fall times	—	3	ns
S9	SWD_DIO input data setup time to SWD_CLK rise	8	—	ns
S10	SWD_DIO input data hold time after SWD_CLK rise	1.4	—	ns
S11	SWD_CLK high to SWD_DIO data valid	—	25	ns
S12	SWD_CLK high to SWD_DIO high-Z	5	—	ns

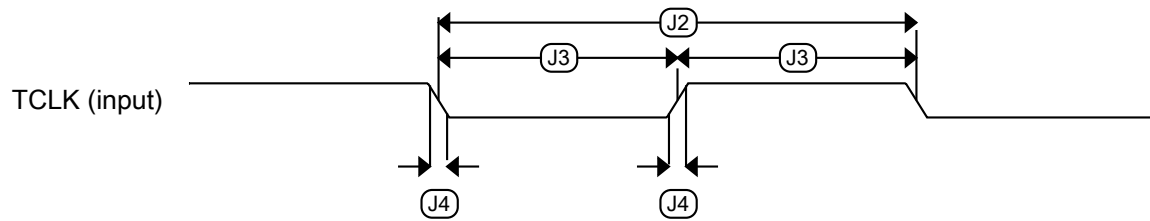


Figure 7. Test clock input timing

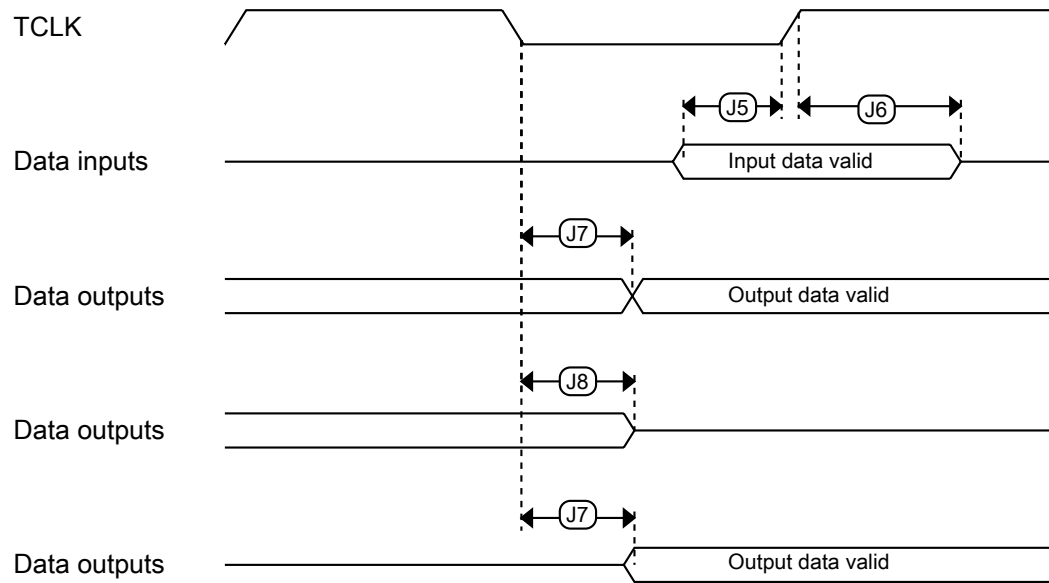


Figure 8. Boundary scan (JTAG) timing

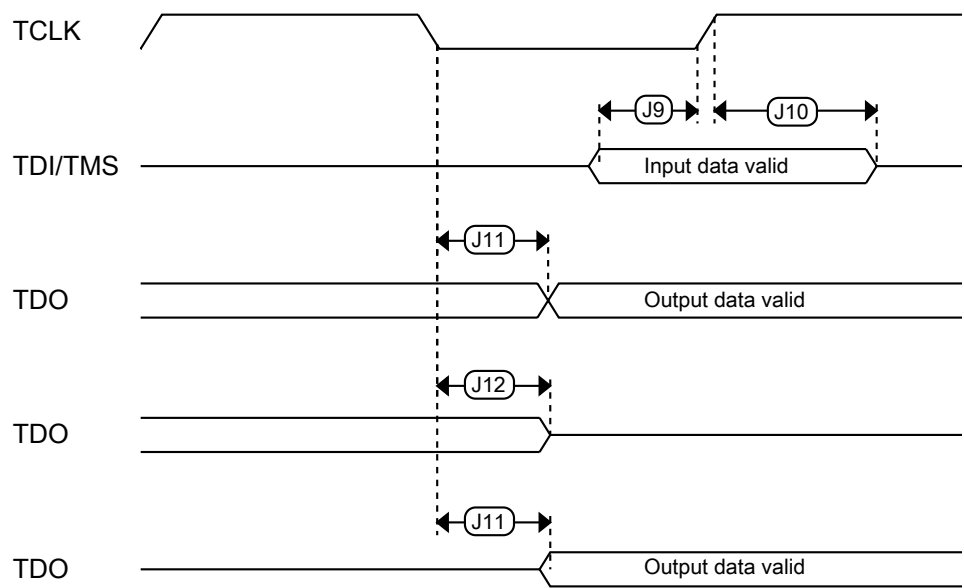


Figure 9. Test Access Port timing

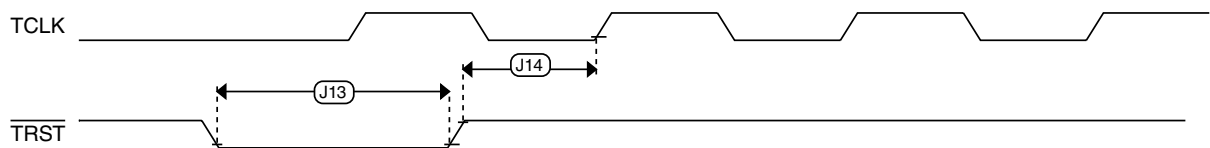


Figure 10. TRST timing

3.2 System modules

There are no specifications necessary for the device's system modules.

3.3 Clock modules

3.3.1 MCG specifications

Table 15. MCG specifications

Symbol	Description		Min.	Typ.	Max.	Unit	Notes
f _{ints_ft}	Internal reference frequency (slow clock) — factory trimmed at nominal VDD and 25 °C		—	32.768	—	kHz	
Δf _{ints_t}	Total deviation of internal reference frequency (slow clock) over voltage and temperature		—	+0.5/-0.7	± 2	%	
f _{ints_t}	Internal reference frequency (slow clock) — user trimmed		31.25	—	39.0625	kHz	
Δf _{dco_res_t}	Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM and SCFTRIM		—	± 0.3	± 0.6	%f _{dco}	1
Δf _{dco_t}	Total deviation of trimmed average DCO output frequency over voltage and temperature		—	+0.5/-0.7	± 2	%f _{dco}	1, 2
Δf _{dco_t}	Total deviation of trimmed average DCO output frequency over fixed voltage and temperature range of 0–70°C		—	± 0.3	± 1.5	%f _{dco}	1
f _{intf_ft}	Internal reference frequency (fast clock) — factory trimmed at nominal VDD and 25°C		—	4	—	MHz	
Δf _{intf_ft}	Frequency deviation of internal reference clock (fast clock) over temperature and voltage — factory trimmed at nominal VDD and 25 °C		—	+1/-2	± 5	%f _{intf_ft}	
f _{intf_t}	Internal reference frequency (fast clock) — user trimmed at nominal VDD and 25 °C		3	—	5	MHz	
f _{loc_low}	Loss of external clock minimum frequency — RANGE = 00		(3/5) x f _{ints_t}	—	—	kHz	
f _{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11		(16/5) x f _{ints_t}	—	—	kHz	
FLL							
f _{fll_ref}	FLL reference frequency range		31.25	—	39.0625	kHz	
f _{dco}	DCO output frequency range	Low range (DRS=00) 640 × f _{fll_ref}	20	20.97	25	MHz	3, 4
		Mid range (DRS=01) 1280 × f _{fll_ref}	40	41.94	50	MHz	
		Mid-high range (DRS=10) 1920 × f _{fll_ref}	60	62.91	75	MHz	
		High range (DRS=11) 2560 × f _{fll_ref}	80	83.89	100	MHz	
f _{dco_t_DMX32}	DCO output frequency	Low range (DRS=00) 732 × f _{fll_ref}	—	23.99	—	MHz	5, 6
		Mid range (DRS=01) 1464 × f _{fll_ref}	—	47.97	—	MHz	
		Mid-high range (DRS=10)	—	71.99	—	MHz	

Table continues on the next page...

3.3.3 Oscillator electrical specifications

3.3.3.1 Oscillator DC electrical specifications

Table 17. Oscillator DC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	—	3.6	V	
I_{DDOSC}	Supply current — low-power mode (HGO=0) 32 kHz 4 MHz 8 MHz (RANGE=01) 16 MHz 24 MHz 32 MHz	—	500	—	nA	1
		—	200	—	μ A	
		—	300	—	μ A	
		—	950	—	μ A	
		—	1.2	—	mA	
		—	1.5	—	mA	
I_{DDOSC}	Supply current — high-gain mode (HGO=1) 32 kHz 4 MHz 8 MHz (RANGE=01) 16 MHz 24 MHz 32 MHz	—	25	—	μ A	1
		—	400	—	μ A	
		—	500	—	μ A	
		—	2.5	—	mA	
		—	3	—	mA	
		—	4	—	mA	
C_x	EXTAL load capacitance	—	—	—		2, 3
C_y	XTAL load capacitance	—	—	—		2, 3
R_F	Feedback resistor — low-frequency, low-power mode (HGO=0)	—	—	—	M Ω	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	M Ω	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	—	—	M Ω	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	M Ω	
R_S	Series resistor — low-frequency, low-power mode (HGO=0)	—	—	—	k Ω	
	Series resistor — low-frequency, high-gain mode (HGO=1)	—	200	—	k Ω	
	Series resistor — high-frequency, low-power mode (HGO=0)	—	—	—	k Ω	
	Series resistor — high-frequency, high-gain mode (HGO=1)					

Table continues on the next page...

Table 24. 16-bit ADC operating conditions (continued)

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
ΔV_{SSA}	Ground voltage	Delta to V_{SS} ($V_{SS} - V_{SSA}$)	-100	0	+100	mV	2
V_{REFH}	ADC reference voltage high		1.13	V_{DDA}	V_{DDA}	V	
V_{REFL}	ADC reference voltage low		V_{SSA}	V_{SSA}	V_{SSA}	V	
V_{ADIN}	Input voltage	16-bit differential mode - All other modes	V_{REFL} V_{REFL}	— —	31/32 * V_{REFH} V_{REFH}	V	
C_{ADIN}	Input capacitance	16-bit mode 8-bit / 10-bit / 12-bit modes	— —	8 4	10 5	pF	
R_{ADIN}	Input series resistance		—	2	5	k Ω	
R_{AS}	Analog source resistance (external)	13-bit / 12-bit modes $f_{ADCK} < 4$ MHz	—	—	5	k Ω	3
f_{ADCK}	ADC conversion clock frequency	$\leq$ 13-bit mode	1.0	—	24.0	MHz	4
f_{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	4
C_{rate}	ADC conversion rate	$\leq$ 13-bit modes No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	20	—	1200	Ksps	5
C_{rate}	ADC conversion rate	16-bit mode No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	37	—	461	Ksps	5

1. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 1.0$ MHz, unless otherwise stated. Typical values are for reference only, and are not tested in production.
2. DC potential difference.
3. This resistance is external to MCU. To achieve the best results, the analog source resistance must be kept as low as possible. The results in this data sheet were derived from a system that had $< 8 \Omega$ analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1 ns.
4. To use the maximum ADC conversion clock frequency, CFG2[ADHSC] must be set and CFG1[ADLPC] must be clear.
5. For guidelines and examples of conversion rate calculation, download the [ADC calculator tool](#).

Table 37. I²C timing (continued)

Characteristic	Symbol	Standard Mode		Fast Mode		Unit
		Minimum	Maximum	Minimum	Maximum	
Data set-up time	$t_{\text{SU; DAT}}$	250 ⁵	—	100 ^{3, 6}	—	ns
Rise time of SDA and SCL signals	t_r	—	1000	20 + 0.1 C_b ⁷	300	ns
Fall time of SDA and SCL signals	t_f	—	300	20 + 0.1 C_b ⁶	300	ns
Set-up time for STOP condition	$t_{\text{SU; STO}}$	4	—	0.6	—	μs
Bus free time between STOP and START condition	t_{BUF}	4.7	—	1.3	—	μs
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	N/A	N/A	0	50	ns

1. The maximum SCL Clock Frequency in Fast mode with maximum bus loading can only be achieved when using the High drive pins across the full voltage range and when using the Normal drive pins and $V_{\text{DD}} \geq 2.7$ V.
2. The master mode I²C deasserts ACK of an address byte simultaneously with the falling edge of SCL. If no slaves acknowledge this address byte, then a negative hold time can result, depending on the edge rates of the SDA and SCL lines.
3. The maximum $t_{\text{HD; DAT}}$ must be met only if the device does not stretch the LOW period (t_{LOW}) of the SCL signal.
4. Input signal Slew = 10 ns and Output Load = 50 pF
5. Set-up time in slave-transmitter mode is 1 IPBus clock period, if the TX FIFO is empty.
6. A Fast mode I²C bus device can be used in a Standard mode I²C bus system, but the requirement $t_{\text{SU; DAT}} \geq 250$ ns must then be met. This is automatically the case if the device does not stretch the LOW period of the SCL signal. If such a device does stretch the LOW period of the SCL signal, then it must output the next data bit to the SDA line $t_{\text{rmax}} + t_{\text{SU; DAT}} = 1000 + 250 = 1250$ ns (according to the Standard mode I²C bus specification) before the SCL line is released.
7. C_b = total capacitance of the one bus line in pF.

Table 38. I²C 1 Mbps timing

Characteristic	Symbol	Minimum	Maximum	Unit
SCL Clock Frequency	f_{SCL}	0	1 ¹	MHz
Hold time (repeated) START condition. After this period, the first clock pulse is generated.	$t_{\text{HD; STA}}$	0.26	—	μs
LOW period of the SCL clock	t_{LOW}	0.5	—	μs
HIGH period of the SCL clock	t_{HIGH}	0.26	—	μs
Set-up time for a repeated START condition	$t_{\text{SU; STA}}$	0.26	—	μs
Data hold time for I ² C bus devices	$t_{\text{HD; DAT}}$	0	—	μs
Data set-up time	$t_{\text{SU; DAT}}$	50	—	ns
Rise time of SDA and SCL signals	t_r	20 + 0.1 C_b ²	120	ns
Fall time of SDA and SCL signals	t_f	20 + 0.1 C_b ²	120	ns
Set-up time for STOP condition	$t_{\text{SU; STO}}$	0.26	—	μs
Bus free time between STOP and START condition	t_{BUF}	0.5	—	μs
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	0	50	ns

1. The maximum SCL clock frequency of 1 Mbps can support maximum bus loading when using the High drive pins across the full voltage range.

To find a package drawing, go to freescale.com and perform a keyword search for the drawing's document number:

If you want the drawing for this package	Then use this document number
64-pin LQFP	98ASS23234W
100-pin LQFP	98ASS23308W

5 Pinout

5.1 KV31F Signal Multiplexing and Pin Assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

100 LQFP	64 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
1	1	PTE0/ CLKOUT32K	ADC1_SE4a	ADC1_SE4a	PTE0/ CLKOUT32K	SPI1_PCS1	UART1_TX			I2C1_SDA		
2	2	PTE1/ LLWU_P0	ADC1_SE5a	ADC1_SE5a	PTE1/ LLWU_P0	SPI1_SOUT	UART1_RX			I2C1_SCL	SPI1_SIN	
3	—	PTE2/ LLWU_P1	ADC1_SE6a	ADC1_SE6a	PTE2/ LLWU_P1	SPI1_SCK	UART1_CTS_b					
4	—	PTE3	ADC1_SE7a	ADC1_SE7a	PTE3	SPI1_SIN	UART1_RTS_b				SPI1_SOUT	
5	—	PTE4/ LLWU_P2	DISABLED		PTE4/ LLWU_P2	SPI1_PCS0	LPUART0_TX					
6	—	PTE5	DISABLED		PTE5	SPI1_PCS2	LPUART0_RX					
7	—	PTE6	DISABLED		PTE6	SPI1_PCS3	LPUART0_CTS_b					
8	3	VDD	VDD	VDD								
9	4	VSS	VSS	VSS								
10	5	PTE16	ADC0_SE4a	ADC0_SE4a	PTE16	SPI0_PCS0	UART2_TX	FTM_CLKIN0		FTM0_FLT3		
11	6	PTE17	ADC0_SE5a	ADC0_SE5a	PTE17	SPI0_SCK	UART2_RX	FTM_CLKIN1		LPTMR0_ALT3		
12	7	PTE18	ADC0_SE6a	ADC0_SE6a	PTE18	SPI0_SOUT	UART2_CTS_b	I2C0_SDA				
13	8	PTE19	ADC0_SE7a	ADC0_SE7a	PTE19	SPI0_SIN	UART2_RTS_b	I2C0_SCL				
14	—	ADC0_DP1	ADC0_DP1	ADC0_DP1								

100 LQFP	64 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
39	27	PTA5	DISABLED		PTA5		FTM0_CH2				JTAG_ TRST_b	
40	—	VDD	VDD	VDD								
41	—	VSS	VSS	VSS								
42	28	PTA12	DISABLED		PTA12		FTM1_CH0				FTM1_QD_ PHA	
43	29	PTA13/ LLWU_P4	DISABLED		PTA13/ LLWU_P4		FTM1_CH1				FTM1_QD_ PHB	
44	—	PTA14	DISABLED		PTA14	SPI0_PCS0	UART0_TX					
45	—	PTA15	DISABLED		PTA15	SPI0_SCK	UART0_RX					
46	—	PTA16	DISABLED		PTA16	SPI0_SOUT	UART0_ CTS_b					
47	—	PTA17	ADC1_SE17	ADC1_SE17	PTA17	SPI0_SIN	UART0_ RTS_b					
48	30	VDD	VDD	VDD								
49	31	VSS	VSS	VSS								
50	32	PTA18	EXTAL0	EXTAL0	PTA18		FTM0_FLT2	FTM_ CLKIN0				
51	33	PTA19	XTAL0	XTAL0	PTA19	FTM0_FLT0	FTM1_FLT0	FTM_ CLKIN1		LPTMR0_ ALT1		
52	34	RESET_b	RESET_b	RESET_b								
53	35	PTB0/ LLWU_P5	ADC0_SE8/ ADC1_SE8	ADC0_SE8/ ADC1_SE8	PTB0/ LLWU_P5	I2C0_SCL	FTM1_CH0			FTM1_QD_ PHA	UART0_RX	
54	36	PTB1	ADC0_SE9/ ADC1_SE9	ADC0_SE9/ ADC1_SE9	PTB1	I2C0_SDA	FTM1_CH1	FTM0_FLT2	EWM_IN	FTM1_QD_ PHB	UART0_TX	
55	37	PTB2	ADC0_SE12	ADC0_SE12	PTB2	I2C0_SCL	UART0_ RTS_b	FTM0_FLT1		FTM0_FLT3		
56	38	PTB3	ADC0_SE13	ADC0_SE13	PTB3	I2C0_SDA	UART0_ CTS_b			FTM0_FLT0		
57	—	PTB9	DISABLED		PTB9	SPI1_PCS1	LPUART0_ CTS_b					
58	—	PTB10	ADC1_SE14	ADC1_SE14	PTB10	SPI1_PCS0	LPUART0_ RX			FTM0_FLT1		
59	—	PTB11	ADC1_SE15	ADC1_SE15	PTB11	SPI1_SCK	LPUART0_ TX			FTM0_FLT2		
60	—	VSS	VSS	VSS								
61	—	VDD	VDD	VDD								
62	39	PTB16	DISABLED		PTB16	SPI1_SOUT	UART0_RX	FTM_ CLKIN0		EWM_IN		
63	40	PTB17	DISABLED		PTB17	SPI1_SIN	UART0_TX	FTM_ CLKIN1		EWM_OUT_ b		
64	41	PTB18	DISABLED		PTB18		FTM2_CH0			FTM2_QD_ PHA		
65	42	PTB19	DISABLED		PTB19		FTM2_CH1			FTM2_QD_ PHB		

Pinout

100 LQFP	64 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
66	—	PTB20	DISABLED		PTB20					CMP0_OUT		
67	—	PTB21	DISABLED		PTB21					CMP1_OUT		
68	—	PTB22	DISABLED		PTB22							
69	—	PTB23	DISABLED		PTB23		SPI0_PCS5					
70	43	PTC0	ADC0_SE14	ADC0_SE14	PTC0	SPI0_PCS4	PDB0_EXTRG			FTM0_FLT1	SPI0_PCS0	
71	44	PTC1/ LLWU_P6	ADC0_SE15	ADC0_SE15	PTC1/ LLWU_P6	SPI0_PCS3	UART1_RTS_b	FTM0_CH0			LPUART0_RTS_b	
72	45	PTC2	ADC0_SE4b/ CMP1_IN0	ADC0_SE4b/ CMP1_IN0	PTC2	SPI0_PCS2	UART1_CTS_b	FTM0_CH1			LPUART0_CTS_b	
73	46	PTC3/ LLWU_P7	CMP1_IN1	CMP1_IN1	PTC3/ LLWU_P7	SPI0_PCS1	UART1_RX	FTM0_CH2	CLKOUT		LPUART0_RX	
74	47	VSS	VSS	VSS								
75	48	VDD	VDD	VDD								
76	49	PTC4/ LLWU_P8	DISABLED		PTC4/ LLWU_P8	SPI0_PCS0	UART1_TX	FTM0_CH3		CMP1_OUT	LPUART0_TX	
77	50	PTC5/ LLWU_P9	DISABLED		PTC5/ LLWU_P9	SPI0_SCK	LPTMR0_ALT2			CMP0_OUT	FTM0_CH2	
78	51	PTC6/ LLWU_P10	CMP0_IN0	CMP0_IN0	PTC6/ LLWU_P10	SPI0_SOUT	PDB0_EXTRG				I2C0_SCL	
79	52	PTC7	CMP0_IN1	CMP0_IN1	PTC7	SPI0_SIN					I2C0_SDA	
80	53	PTC8	ADC1_SE4b/ CMP0_IN2	ADC1_SE4b/ CMP0_IN2	PTC8							
81	54	PTC9	ADC1_SE5b/ CMP0_IN3	ADC1_SE5b/ CMP0_IN3	PTC9					FTM2_FLT0		
82	55	PTC10	ADC1_SE6b	ADC1_SE6b	PTC10	I2C1_SCL						
83	56	PTC11/ LLWU_P11	ADC1_SE7b	ADC1_SE7b	PTC11/ LLWU_P11	I2C1_SDA						
84	—	PTC12	DISABLED		PTC12							
85	—	PTC13	DISABLED		PTC13							
86	—	PTC14	DISABLED		PTC14							
87	—	PTC15	DISABLED		PTC15							
88	—	VSS	VSS	VSS								
89	—	VDD	VDD	VDD								
90	—	PTC16	DISABLED		PTC16		LPUART0_RX					
91	—	PTC17	DISABLED		PTC17		LPUART0_TX					
92	—	PTC18	DISABLED		PTC18		LPUART0_RTS_b					
93	57	PTD0/ LLWU_P12	DISABLED		PTD0/ LLWU_P12	SPI0_PCS0	UART2_RTS_b	FTM0_CH0		LPUART0_RTS_b		
94	58	PTD1	ADC0_SE5b	ADC0_SE5b	PTD1	SPI0_SCK	UART2_CTS_b	FTM0_CH1		LPUART0_CTS_b		

100 LQFP	64 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
95	59	PTD2/LLWU_P13	DISABLED		PTD2/LLWU_P13	SPI0_SOUT	UART2_RX	FTM0_CH2		LPUART0_RX	I2C0_SCL	
96	60	PTD3	DISABLED		PTD3	SPI0_SIN	UART2_TX	FTM0_CH3		LPUART0_TX	I2C0_SDA	
97	61	PTD4/LLWU_P14	DISABLED		PTD4/LLWU_P14	SPI0_PCS1	UART0_RTS_b	FTM0_CH4		EWM_IN	SPI1_PCS0	
98	62	PTD5	ADC0_SE6b	ADC0_SE6b	PTD5	SPI0_PCS2	UART0_CTS_b	FTM0_CH5		EWM_OUT_b	SPI1_SCK	
99	63	PTD6/LLWU_P15	ADC0_SE7b	ADC0_SE7b	PTD6/LLWU_P15	SPI0_PCS3	UART0_RX	FTM0_CH6		FTM0_FLT0	SPI1_SOUT	
100	64	PTD7	DISABLED		PTD7		UART0_TX	FTM0_CH7		FTM0_FLT1	SPI1_SIN	

5.2 Recommended connection for unused analog and digital pins

The following table shows the recommended connections for analog interface pins if those analog interfaces are not used in the customer's application.

Table 39. Recommended connection for unused analog interfaces

Pin Type		Short recommendation	Detailed recommendation
Analog/non GPIO	PGAx/ADCx	Float	Analog input - Float
Analog/non GPIO	ADCx/CMPx	Float	Analog input - Float
Analog/non GPIO	VREF_OUT	Float	Analog output - Float
Analog/non GPIO	DACx_OUT	Float	Analog output - Float
Analog/non GPIO	RTC_WAKEUP_B	Float	Analog output - Float
Analog/non GPIO	XTAL32	Float	Analog output - Float
Analog/non GPIO	EXTAL32	Float	Analog input - Float
GPIO/Analog	PTA18/EXTAL0	Float	Analog input - Float
GPIO/Analog	PTA19/XTAL0	Float	Analog output - Float
GPIO/Analog	PTx/ADCx	Float	Float (default is analog input)
GPIO/Analog	PTx/CMPx	Float	Float (default is analog input)
GPIO/Digital	PTA0/JTAG_TCLK	Float	Float (default is JTAG with pulldown)
GPIO/Digital	PTA1/JTAG_TDI	Float	Float (default is JTAG with pullup)
GPIO/Digital	PTA2/JTAG_TDO	Float	Float (default is JTAG with pullup)
GPIO/Digital	PTA3/JTAG_TMS	Float	Float (default is JTAG with pullup)
GPIO/Digital	PTA4/NMI_b	10k Ω pullup or disable and float	Pull high or disable in PCR & FOPT and float

Table continues on the next page...

6 Part identification

6.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

6.2 Format

Part numbers for this device have the following format:

Q KV## A FFF R T PP CC S N

6.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	- M = Fully qualified, general market flow - P = Prequalification
KV##	Kinetis V Series	KV3x: Cortex-M4 based MCU
A	Key attribute	- D = Cortex-M4 w/ DSP - F = Cortex-M4 w/ DSP and FPU
FFF	Program flash memory size	64 = 64 KB 128 = 128 KB 256 = 256 KB 512 = 512 KB
R	Silicon revision	(Blank) = Main - A = Revision after main
T	Temperature range (°C)	- V = -40 to 105 - C = -40 to 85
PP	Package identifier	- FM = 32 QFN (5 mm x 5 mm) - LF = 48 LQFP (7 mm x 7 mm) - LH = 64 LQFP (10 mm x 10 mm) - LL = 100 LQFP (14 mm x 14 mm) - MC = 121 XFBGA (8 mm x 8 mm) - DC = 121 XFBGA (8 mm x 8 mm x 0.5 mm)
CC	Maximum CPU frequency (MHz)	10 = 100 MHz 12 = 120 MHz

Table continues on the next page...

Table 40. Revision History (continued)

Rev. No.	Date	Substantial Changes
		- Updated the Part Number Example - Updated IRC48M specifications table
6	10/2015	- In "Power consumption operating behaviors" section, added "Low power mode peripheral adders—typical value" table - In "Thermal operating requirements" table, in footnote, corrected "$T_J = T_A + \Theta_{JA}$" to "$T_J = T_A + R_{\Theta JA}$" - Updated "IRC48M specifications" table - Updated "NVM program/erase timing specifications" table; updated values for t_{hversall} (Erase All high-voltage time) - In "Slave mode DSPI timing (limited voltage range)" table, added footnote regarding maximum frequency of operation - Added new section, "Recommended connections for unused analog and digital pins"
5	4/2015	- On page 1: - Under "Communication interfaces," updated I²C bullet to indicate support for up to 1 Mbps operation - Under "Operating characteristics," specified that voltage range includes flash writes - In "Voltage and current operating requirements" table: - Removed content related to positive injection - Updated footnote 1 to say that all analog and I/O pins are internally clamped to V_{SS} only (not V_{SS} and V_{DD}) through ESD protection diodes. - In "Power consumption operating behaviors" table: - Added additional temperature data in power consumption table - Added Max IDD values based on characterization results equivalent to mean + 3 sigma - Updated "EMC radiated emissions operating behaviors" table - In "Thermal operating requirements" table, added the following footnote for ambient temperature: "Maximum T_A can be exceeded only if the user ensures that T_J does not exceed maximum T_J. The simplest method to determine T_J is: $T_J = T_A + \Theta_{JA} \times \text{chip power dissipation}$" - Updated "IRC48M Specifications": - Updated maximum values for $\Delta_{\text{firc48m_lv}}$ and $\Delta_{\text{firc48m_hv}}$ (full temperature) - Added specifications for $\Delta_{\text{firc48m_hv}}$ (-40°C to 85°C) - In "I²C timing" table, - Added the following footnote on maximum Fast mode value for SCL Clock Frequency: "The maximum SCL Clock Frequency in Fast mode with maximum bus loading can only be achieved when using the High drive pins across the full voltage range and when using the Normal drive pins and VDD ≥ 2.7 V." - Updated minimum Fast mode value for LOW period of the SCL clock to 1.25 μs - Added "I²C 1 Mbps timing" table - Specified that the figure, "KV31F 64 LQFP Pinout Diagram" is a top view - Specified that the figure, "KV31F 100 LQFP Pinout Diagram" is a top view - Removed Section 6, "Ordering parts."
4	7/2014	In "Power consumption operating behaviors table": - Updated existing typical power measurements - Added new typical power measurements for the following: - IDD_HSRUN (High Speed Run mode current executing CoreMark code) - IDD_RUNCO (Run mode current in Compute operation, executing CoreMark code) - IDD_RUN (Run mode current in Compute operation, executing while(1) loop)

Table continues on the next page...

Table 40. Revision History (continued)

Rev. No.	Date	Substantial Changes
		• IDD_VLPR (Very Low Power mode current executing CoreMark code) • IDD_VLPR (Very Low Power Run mode current in Compute operation, executing while(1) loop)
3	5/2014	• In "Voltage and current operating ratings" table, updated maximum digital supply current • Updated "Voltage and current operating behaviors" table • Updated "Power mode transition operating behaviors" table • Updated "Power consumption operating behaviors" table • Updated "EMC radiated emissions operating behaviors for 64 LQFP package" table • Updated "Thermal attributes" table • Updated "MCG specifications" table • Updated "IRC48M specifications" table • Updated "16-bit ADC operating conditions" table • Updated "Voltage reference electrical specifications" section • Added "121-pin XFBGA part marking" table • Added "64-pin MAPBGA part marking" table
2	4/2014	• Updated "Voltage and current operating behaviors" table • Updated "Thermal attributes" table • Updated "IRC48M specifications" table
1	3/2014	Initial public release